











ZHCSGR3A -MAY 2017-REVISED AUGUST 2017

bq25606

# 用于高输入电压和窄电压直流 (NVDC) 电源路径管理的 bq25606 独立 3.0A 单节电池充电器

# 1 特性

- 高效 1.5MHz 同步开关模式降压充电器
  - 在 2A 电流 (5V 输入) 下具有 92% 的充电效率
  - 针对 USB 电压输入 (5V) 进行了优化
- 支持 USB On-The-Go (OTG)
  - 具有高达 1.2A 输出的升压转换器
  - 在 1A 输出下具有 92% 的升压效率
  - 精确的恒定电流 (CC) 限制
  - 高达 500µF 电容负载的软启动
  - 输出短路保护
- 单个输入,支持 USB 输入和高电压适配器
  - 支持 3.9V 至 13.5V 输入电压范围,绝对最大输入电压额定值为 22V
  - 通过高达 4.6V 的输入电压限制 (VINDPM) 进行 最大功率跟踪
  - VINDPM 阈值自动跟踪电池电压
  - 自动检测 USB SDP、DCP 以及非标准适配器
- 高电池放电效率,电池放电 MOSFET 为 19.5mΩ
- 窄 VDC (NVDC) 电源路径管理
  - 无需电池或深度放电的电池即可瞬时启动
  - 电池充电模式下的理想二极管运行
- 高集成度,包括所有 MOSFET、电流感应和环路补 。
- 在系统待机电压下具有 58µA 的低电池泄漏电流
- 高精度
  - ±0.5% 充电电压调节
  - ±6% 1.2A 和 1.8A 充电电流调节
  - ±5% 0.5A、1.2A 和 1.8A 输入电流调节
- 使用 bq25606 并借助 WEBENCH® 电源设计器 创建定制设计

# 2 应用

- EPOS、便携式扬声器、电子烟
- 便携式互联网设备和附件

# 3 说明

bq25606 器件高度集成的 独立 3.0A 开关模式电池充电管理和系统电源路径管理器件,适用于单节锂离子和锂聚合物电池。低阻抗电源路径对开关模式运行效率进行了优化、缩短了电池充电时间并延长了放电阶段的电池使用寿命。

# 器件信息(1)

器件型号	封装	封装尺寸 (标称值)
bq25606	VQFN (24)	4.00mm x 4.00mm

(1) 如需了解所有可用封装,请参阅产品说明书末尾的可订购产品 附录。

# 简化应用 VBUS SW BTST ILIM SYS ICHG REGN VSET TS



1	特性 1		8.3 Feature Description	1
2	应用 1	9	Application and Implementation	2
3	说明1		9.1 Application information	
4	修订历史记录		9.2 Typical Application Diagram	26
5	说明(续)3		9.3 Application Curves	28
6	Pin Configuration and Functions	10	Power Supply Recommendations	33
7	Specifications6	11	Layout	34
•	7.1 Absolute Maximum Ratings		11.1 Layout Guidelines	34
	7.2 ESD Ratings		11.2 Layout Example	34
	7.3 Recommended Operating Conditions	12	器件和文档支持	36
	7.4 Thermal information		12.1 文档支持	36
	7.5 Timing Requirements		12.2 社区资源	30
	7.6 Electrical Characteristics		12.3 商标	30
	7.7 Typical Characteristics		12.4 静电放电警告	30
8	Detailed Description		12.5 Glossary	30
9	8.1 Overview	13	机械、封装和可订购信息	37
	8.2 Functional Block Diagram			

# 4 修订历史记录

注: 之前版本的页码可能与当前版本有所不同。

Changes from Original (May 2017) to Revision A	Page
● 更新了产品说明书标题	1
<ul><li>更新了产品说明书标题</li><li>己删除 200nS 快速关闭 特性</li></ul>	1
• 更新了简化应用 原理图	1
Changed ACDRV pin references to "NC" in <i>Pin Configuration and Functions</i> section	4
Deleted ACDRV pin references from Pin Functions table	
Updated VAC pin description in Pin Functions table	5
Deleted ACDRV pin references from Absolute Maximum Ratings table	6
Added ESD Ratings table	6
Deleted VAC debounce time from Timing Requirements table	7
Updated Functional Block Diagram	16
Updated Power Up from Input Source section	17
• 己删除 Power Up OVPFET section	17
• 己删除 OVPFET Startup Control timing illustration	
Updated Input Overvoltage (ACOV) section	<u>2</u> 4
Updated bq25606 Application Diagram schematic	26



# 5 说明 (续)

bq25606高度集成的独立3.0A 开关模式电池充电管理和系统电源路径管理器件,适用于单节锂离子和锂聚合物电池。该器件可针对各种独立充电器和便携式设备实现快速充电,并提供高输入电压支持。其低阻抗电源路径对开关模式运行效率进行了优化、缩短了电池充电时间并延长了放电阶段的电池使用寿命。其输入电压和电流调节可以为电池提供最大的充电功率。该解决方案在系统和电池之间高度集成输入反向阻断场 FET(RBFET,Q1)、高侧开关 FET(HSFET,Q2)、低侧开关 FET(LSFET,Q3)以及电池 FET(BATFET、Q4)。它还集成了自举二极管以进行高侧栅极驱动,从而简化系统设计。

该器件支持多种输入源,包括标准 USB 主机端口、USB 充电端口以及兼容 USB 的高电压适配器。该器件根据内置 USB 接口设置默认输入电流限值。 该器件符合 USB 2.0 和 USB 3.0 电源规范,具有输入电流和电压调节功能。当器件内置 USB 接口确定输入适配器未知时,器件的输入电流限值由 ILIM 引脚设置电阻器值决定。 该器件还具有高达 1.2A 的很定电流限制能力,能够为 VBUS 提供 5.15V 的电压,符合 USB On-the-Go (OTG) 运行功率额定值规范。

电源路径管理将系统电压调节至稍高于电池电压的水平,但是不会下降至 3.5V 最小系统电压以下。借助于这个特性,即使在电池电量完全耗尽或者电池被拆除时,系统也能保持运行。当达到输入电流限值或电压限值时,电源路径管理自动将充电电流减少为 0。随着系统负载持续增加,电源路径在满足系统电源需求之前将电池放电。该补充模式可防止输入源过载。

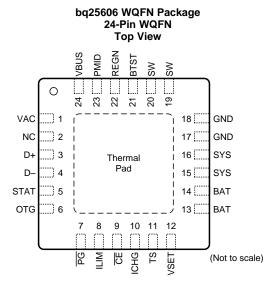
此器件在无需软件控制情况下启动并完成一个充电周期。它感应电池电压并通过三个阶段为电池充电: 预充电、恒定电流和恒定电压。在充电周期的末尾,当充电电流低于预设限值并且电池电压高于再充电阈值时,充电器自动终止。如果已完全充电的电池降至再充电阈值以下,则充电器自动启动另一个充电周期。

此充电器提供针对电池充电和系统运行的多种安全 功能, 其中包括电池负温度系数热敏电阻监视、充电安全计时器以及过压和过流保护。当结温超过 110℃时, 热调节会减小充电电流。STAT 输出报告充电状态和任何故障状况。其他安全 功能 包括针对充电和升压模式的电池温度感应、热调节和热关断以及输入 UVLO 和过压保护。

该器件系列采用 24 引脚 4mm x 4mm QFN 封装。



# 6 Pin Configuration and Functions



Terr	minal	1/0	Bassaluttan	
Name	No.	1/0	Description	
NC	2		No connection. This pin must be floating.	
BAT 13 P		D	Battery connection point to the positive terminal of the battery pack. The internal current sensing resistor	
		r	is connected between SYS and BAT. Connect a 10 μF closely to the BAT pin.	
BTST	21	Р	PWM high side driver positive supply. internally, the BTST is connected to the cathode of the boost-strap diode. Connect the $0.047$ - $\mu F$ bootstrap capacitor from SW to BTST.	
CE	9	DI	Charge enable pin. When this pin is driven low, battery charging is enabled.	
D+	3	AIO	Positive line of the USB data line pair. D+/D- based USB host/charging port detection. The detection includes data contact detection (DCD), primary and secondary detection in BC1.2 and nonstandard adaptors	
D-	4	AIO	Negative line of the USB data line pair. D+/D- based USB host/charging port detection. The detection includes data contact detection (DCD), primary and secondary detection in BC1.2 and nonstandard adaptors	
CND 17			Device are and and since I are and	
GND	18		Power ground and signal ground	
ICHG	10	Al	$I_{CHG}$ pin sets the charge current limit. A resistor is connected from $I_{CHG}$ pin to ground to set charge current limit as $I_{CHG} = K_{ICHG}/R_{ICHG}$ . The acceptable range for charge current is 300 mA – 3000 mA.	
ILIM	8	Al	ILIM sets the input current limit. A resistor is connected from ILIM pin to ground to set the input current limit as IINDPM = $K_{\rm ILIM}/R_{\rm ILIM}$ . The acceptable range for ILIM current is 500 mA - 3200 mA. The resistor based input current limit is effective only when the input adapter is detected as unknown. Otherwise, the input current limit is determined by D+/D- detection outcome.	
OTG	6	DI	Boost mode enable pin. When this pin is pulled HIGH, OTG is enabled. OTG cannot be floating.	
PG	7	DO	Open drain active low power good indicator. Connect to the pull up rail through 10 k $\Omega$ resistor. LOW indicates a good input if the input voltage is between UVLO and ACOV, above SLEEP mode threshold, and input current limit is above 30 mA.	
PMID	23	Р	Connected to the drain of the reverse blocking MOSFET (RBFET) and the drain of HSFET. Put a 10 - $\mu$ F ceramic capacitor between PMID and GND.	
REGN	22	Р	PWM low side driver positive supply output. Internally, REGN is connected to the anode of the boost-strap diode. Connect a 4.7- $\mu$ F (10-V rating) ceramic capacitor from REGN to analog GND. The capacitor should be placed close to the IC.	



# (continued)

Terminal I/O		1/0	Description			
Name	No.	1/0	Description			
STAT	5	DO	Open-drain interrupt output. Connect the STAT pin to a logic rail via 10-k $\Omega$ resistor. The STAT pin indicates charger status. Charge in progress: LOW Charge complete or charger in SLEEP mode: HIGH Charge suspend (fault response): BlinK at 1Hz			
	19		Switching node connecting to output inductor. Internally SW is connected to the source of the n-channel			
SW	20	Р	HSFET and the drain of the n-channel LSFET. Connect the 0.047-μF bootstrap capacitor from SW to BTST.			
SYS	15	Р	Converter output connection point. The internal current sensing resistor is connected between SYS and			
16		F	BAT. Connect a 20 µF capacitor close to the SYS pin.			
TS	11	Al	Temperature qualification voltage input to support JEITA profile. Connect a negative temperature coefficient thermistor. Program temperature window with a resistor divider from REGN to TS to GND. Charge suspends when TS pin voltage is out of range. Recommend 103AT-2 thermistor.			
VAC	1	Al	Input voltage sensing. This pin must be shorted to VBUS pin.			
VBUS	24	Р	Charger input voltage. The internal n-channel reverse block MOSFET (RBFET) is connected between VBUS and PMID with VBUS on source. Place a 1-uF ceramic capacitor from VBUS to GND and place it as close as possible to IC.			
VSET 12 AI		Al	VSET pin sets default battery charge voltage in bq25606. Program battery regulation voltage with a resistor pull-down from VSET to GND. $R_{PD} > 50k\Omega \text{ (float pin)} = 4.208 \text{ V} \\ R_{PD} < 500\Omega \text{ (short to GND)} = 4.352 \text{ V} \\ 5k\Omega < R_{PD} < 25k\Omega = 4.400 \text{ V}$			
Thermal Pad P		Р	Ground reference for the device that is also the thermal pad used to conduct heat from the device. This connection serves two purposes. The first purpose is to provide an electrical ground connection for the device. The second purpose is to provide a low thermal-impedance path from the device die to the PCB. This pad should be tied externally to a ground plane.			



# 7 Specifications

# 7.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

		MIN	MAX	UNIT
Voltage Range (with respect to GND)	VAC	-2	22	V
Voltage Range (with respect to GND)	VBUS (converter not switching) (2)	-2	22	V
Voltage Range (with respect to GND)	BTST, PMID (converter not switching) (2)	-0.3	22	V
Voltage Range (with respect to GND)	SW	-2	16	V
Voltage Range (with respect to GND)	BTST to SW	-0.3	7	V
Voltage Range (with respect to GND)	D+, D-	-0.3	7	V
Voltage Range (with respect to GND)	REGN, TS, $\overline{\text{CE}}$ , $\overline{\text{PG}}$ , BAT, SYS (converter not switching)	-0.3	7	V
Output Sink Current	STAT		6	mA
Voltage Range (with respect to GND)	VSET, ILIM, ICHG, OTG	-0.3	7	V
Voltage Range (with respect to GND)	PGND to GND (QFN package only)	-0.3	0.3	V
Operating junction temperature, T	Operating junction temperature, T <sub>J</sub>		150	°C
Storage temperature, T <sub>stg</sub>		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. All voltage values are with respect to the network ground terminal unless otherwise noted.

(2) VBUS is specified up to 22 V for a maximum of one hour at room temperature

# 7.2 ESD Ratings

			VALUE	UNIT
		Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins <sup>(1)</sup>	±2000	
V <sub>(ESD)</sub>	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins (2)	±250	V

<sup>1)</sup> JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

# 7.3 Recommended Operating Conditions

		MIN	NOM	MAX	UNIT
V <sub>BUS</sub>	Input voltage	3.9		13.5 <sup>(1)</sup>	V
I <sub>in</sub>	Input current (VBUS)			3.25	Α
I <sub>SYSOP</sub>	Output current (SW)			3.0	Α
$V_{BATOP}$	Battery voltage			4.4	٧
I <sub>BATOP</sub>	Fast charging current			3.0	Α
I <sub>BATOP</sub>	Discharging current (continuous)			6	Α
T <sub>A</sub>	Operating ambient temperature	-40		85	°C

<sup>(1)</sup> The inherent switching noise voltage spikes should not exceed the absolute maximum voltage rating on either the BTST or SW pins. A tight layout minimizes switching noise.

<sup>(2)</sup> JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



# 7.4 Thermal information

	THERMAL METRIC	RGE (VQFN)	UNIT
		24 Pins	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	31.9	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	27	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	9.2	°C/W
$\Psi_{JT}$	Junction-to-top characterization parameter	0.4	°C/W
$\Psi_{JB}$	Junction-to-board characterization parameter	9.2	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	2.8	°C/W

# 7.5 Timing Requirements

	Parameter	Additional infor mAtion	Min	NOM	mAX	UNIT	
VBUS/BAT POWER UP							
t <sub>ACOV</sub>	VBUS OVP reaction time	VAC rising above ACOV threshold to turn off Q2		200		ns	
t <sub>BADSRC</sub>	Bad adapter detection duration			30		ms	
t <sub>TERM_DGL</sub>	Deglitch time for charge termination			250		ms	
t <sub>RECHG_DGL</sub>	Deglitch time for recharge			250		ms	
t <sub>SYSOVLD_DGL</sub>	System over-current deglitch time to turn off Q4			100		μs	
t <sub>BATOVP</sub>	Battery overvoltage deglitch time to disable charge			1		μs	
t <sub>SAFETY</sub>	Typical Charge Safety Timer Range		8	10	12	hr	

# 7.6 Electrical Characteristics

 $V_{VAC\_PRESENT} < V_{VAC\_OV}$  and  $V_{VAC} > V_{BAT} + V_{SLEEP}$ ,  $T_J = -40^{\circ}C$  to 125°C and  $T_J = 25^{\circ}C$  for typical values (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT			
QUIESCENT CU	QUIESCENT CURRENTS								
I <sub>BAT</sub>	Battery discharge current (BAT, SW, SYS) in buck mode	V <sub>BAT</sub> = 4.5 V, V <sub>BUS</sub> < V <sub>AC-UVLOZ</sub> , leakage between BAT and VBUS, T <sub>J</sub> < 85°C			5	μΑ			
I <sub>BAT</sub>	Battery discharge current (BAT, SW, SYS)	V <sub>BAT</sub> = 4.5 V, No VBUS, T <sub>J</sub> < 85°C		58	85	μΑ			
I <sub>VBUS</sub>	Input supply current (VBUS) in buck mode	V <sub>VBUS</sub> = 12 V, V <sub>VBUS</sub> > V <sub>VBAT</sub> , converter not switching		1.5	3	mA			
I <sub>VBUS</sub>	Input supply current (VBUS) in buck mode	$V_{VBUS} > VUVLO, V_{VBUS} > V_{VBAT},$ converter switching, VBAT = 3.8V, ISYS = 0A		3		mA			
I <sub>BOOST</sub>	Battery discharge current in boost mode	V <sub>BAT</sub> = 4.2 V, boost mode, I <sub>VBUS</sub> = 0 A, converter switching		3		mA			
VBUS, VAC AND	D BAT PIN POWER-UP								
V <sub>BUS_OP</sub>	VBUS operating range	V <sub>VBUS</sub> rising	3.9		13.5	V			
V <sub>VAC_PRESENT</sub>	REGN turn-on threshold	V <sub>VAC</sub> rising	3.36	3.65	3.97	V			
V <sub>VAC_PRESENT_H</sub>		V <sub>VAC</sub> falling		300		mV			
V <sub>SLEEP</sub>	Sleep mode falling threshold	$(V_{VAC}-V_{VBAT})$ , $V_{BUSMIN\_FALL} \le V_{BAT} \le V_{REG}$ , VAC falling	37	76	126	mV			
V <sub>SLEEPZ</sub>	Sleep mode rising threshold	$(V_{VAC}-V_{VBAT})$ , $V_{BUSMIN\_FALL} \le V_{BAT} \le V_{REG}$ , VAC rising	130	220	350	mV			
V <sub>VAC_OV_RISE</sub>	VAC Overvoltage rising threshold	VAC rising	13.5	14.28	14.91	V			
V <sub>VAC_OV_HYS</sub>	VAC Overvoltage hysteresis	VAC falling		520		mV			



 $V_{VAC\_PRESENT} < V_{VAC\_OV}$  and  $V_{VAC} > V_{BAT} + V_{SLEEP}$ ,  $T_J = -40^{\circ}C$  to 125°C and  $T_J = 25^{\circ}C$  for typical values (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V <sub>BAT_DPL_FALL</sub>	Battery depletion falling threshold (Q4 turn-off threshold)	V <sub>BAT</sub> falling	2.15		2.6	V
V <sub>BAT_DPL_RISE</sub>	Battery Depletion rising threshold (Q4 turn-on threshold)	V <sub>BAT</sub> rising	2.35		2.82	V
V <sub>BAT_DPL_HYST</sub>	Battery Depletion rising hysteresis	V <sub>BAT</sub> rising		180		mV
V <sub>BUSMIN_FALL</sub>	Bad adapter detection falling threshold	V <sub>BUS</sub> falling	3.65	3.8	3.93	V
V <sub>BUSMIN_HYST</sub>	Bad adapter detection hysteresis			200		mV
I <sub>BADSRC</sub>	Bad adapter detection current source	Sink current from VBUS to GND		30		mA
POWER-PATH						
V <sub>SYS_MIN</sub>	System regulation voltage	V <sub>VBAT</sub> < V <sub>SYS_MIN = 3.5V</sub> , charge enabled or disabled	3.5	3.68		V
V <sub>SYS</sub>	System regulation voltage	$I_{SYS} = 0 \text{ A}, V_{VBAT} > V_{SYSMIN},$ charge disabled		V <sub>BAT</sub> + 50 mV		V
R <sub>ON(RBFET)</sub>	Top reverse blocking MOSFET on- resistance between VBUS and PMID - Q1	-40°C≤ T <sub>A</sub> ≤ 125°C		45		mΩ
R <sub>ON(HSFET)</sub>	Top switching MOSFET on-resistance between PMID and SW - Q2	V <sub>REGN</sub> = 5 V , -40°C≤ T <sub>A</sub> ≤ 125°C		62		mΩ
R <sub>ON(LSFET)</sub>	Bottom switching MOSFET on- resistance between SW and GND - Q3	V <sub>REGN</sub> = 5 V , -40°C≤ T <sub>A</sub> ≤ 125°C		70		mΩ
V <sub>FWD</sub>	BATFET forward voltage in supplement mode			30		mV
R <sub>ON(BAT-SYS)</sub>	SYS-BAT MOSFET on-resistance	QFN package, Measured from BAT to SYS, V <sub>BAT</sub> = 4.2V, T <sub>J</sub> = 25°C		19.5	24	mΩ
R <sub>ON(BAT-SYS)</sub>	SYS-BAT MOSFET on-resistance	QFN package, Measured from BAT to SYS, V <sub>BAT</sub> = 4.2V, T <sub>J</sub> = -40 - 125°C		19.5	30	mΩ
BATTERY CHAR	RGER					
		$R_{VSET} > 50 \text{ k}\Omega, -40 \le T_{J} \le 85^{\circ}\text{C}$	4.187	4.208	4.229	V
V <sub>BATREG</sub>	Charge voltage	$R_{VSET} < 500 \Omega$ , $-40 \le T_{J} \le 85$ °C	4.330	4.352	4.374	V
		$R_{VSET} = 10 \text{ k}\Omega, -40 \le T_{J} \le 85^{\circ}\text{C}$	4.378	4.4	4.422	V
V <sub>BATREG_ACC</sub>	Charge voltage setting accuracy	$V_{BAT} = 4.208 \text{ V or } V_{BAT} = 4.352$ V, -40 \le T <sub>J</sub> \le 85°C	-0.5%		0.5%	
I <sub>CHG_REG_RANGE</sub>	Charge current regulation range		0		3000	mA
I <sub>CHG_REG</sub>	Charge current regulation	$R_{ICHG}$ = 1100 $\Omega$ , $V_{VBAT}$ = 3.1 $V$ or $V_{VBAT}$ = 3.8 $V$	516	615	715	mA
I <sub>CHG_REG_ACC</sub>	Charge current regulation accuracy	$R_{ICHG}$ = 1100 $\Omega$ , $V_{VBAT}$ = 3.1 $V$ or $V_{VBAT}$ = 3.8 $V$	-16%		16%	
I <sub>CHG_REG</sub>	Charge current regulation	$R_{ICHG}$ = 562 $\Omega$ , $V_{VBAT}$ = 3.1 V or $V_{VBAT}$ = 3.8 V	1.14	1.218	1.28	Α
I <sub>CHG_REG</sub>	Charge current regulation accuracy	$R_{ICHG}$ = 562 $\Omega$ , $V_{BAT}$ = 3.1 V or $V_{BAT}$ = 3.8 V	-6%		6%	
I <sub>CHG_REG</sub>	Charge current regulation	$R_{ICHG} = 372 \Omega$ , $V_{VBAT} = 3.1 V$ or $V_{VBAT} = 3.8 V$	1.715	1.813	1.89	А
I <sub>CHG_REG_ACC</sub>	Charge current regulation accuracy	$R_{ICHG}$ = 372 $\Omega$ , $V_{VBAT}$ = 3.1 V or $V_{VBAT}$ = 3.8 V	-5%		5%	
K <sub>ICHG</sub>	Charge current regulation setting ratio	$R_{ICHG} = 372 \Omega, 562 \Omega V_{VBAT} = 3.1 V \text{ or } V_{VBAT} = 3.8 V$	639	677	715	ΑχΩ
K <sub>ICHG_ACC</sub>	Charge current regulation setting ratio accuracy	$R_{ICHG} = 372\Omega$ , 562 $\Omega$ $V_{VBAT} = 3.1$ V or $V_{VBAT} = 3.8$ V	-6%		6%	
V <sub>BATLOWV_FALL</sub>	Battery LOWV falling threshold	Fast charge to precharge	2.67	2.8	2.87	V



 $V_{VAC\_PRESENT} < V_{VAC\_OV}$  and  $V_{VAC} > V_{BAT} + V_{SLEEP}$ ,  $T_J = -40^{\circ}C$  to 125°C and  $T_J = 25^{\circ}C$  for typical values (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V <sub>BATLOWV_RISE</sub>	Battery LOWV rising threshold	Pre-charge to fast charge	3.0	3.1	3.24	V
I <sub>PRECHG</sub>	Precharge current regulation	$R_{ICHG}$ = 1100 $\Omega$ , $V_{VBAT}$ = 2.6 V, $I_{PRECHG}$ = 5% of $I_{CHG}$ = 615mA	21		38	mA
I <sub>PRECHG_ACC</sub>	Precharge current regulation accuracy	Percentage of $I_{CHG}$ , $R_{ICHG}$ = 1100 $\Omega$ , $V_{VBAT}$ = 2.6 V, $I_{CHG}$ = 615mA			6.2%	
I <sub>PRECHG</sub>	Precharge current regulation	$R_{ICHG} = 562 \Omega$ , $V_{VBAT} = 2.6 V$ , $I_{PRECHG} = 5\%$ of $I_{CHG} = 1.218A$	48		67	mA
I <sub>PRECHG_ACC</sub>	Precharge current regulation accuracy	Percentage of $I_{CHG}$ , $R_{ICHG}$ = 562 $\Omega$ , V1330 = 2.6 V, $I_{CHG}$ = 1.218A	3.9%		5.5%	
I <sub>PRECHG</sub>	Precharge current regulation	$R_{ICHG}$ = 372 $\Omega$ , $V_{VBAT}$ = 2.6 V, $I_{PRECHG}$ = 5% of $I_{CHG}$ = 1.813A	76		97	mA
I <sub>PRECHG_ACC</sub>	Precharge current regulation accuracy	Percentage of $I_{CHG}$ , $R_{ICHG}$ = 372 $\Omega$ , $V_{VBAT}$ = 2.6 V, $I_{CHG}$ = 1.813A	4.1%		5.4%	
I <sub>TERM</sub>	Termination current regulation	$R_{ICHG} = 562 \Omega$ , $V_{VBAT} = 4.35V$ , $_{CHG} = 1.218A$	26		100	mA
I <sub>TERM_ACC</sub>	Termination current regulation accuracy	Percentage of $I_{CHG}$ , $R_{ICHG}$ = 562 $\Omega$ , $V_{VBAT}$ = 4.35 V, $I_{CHG}$ = 1.218 A	2.1%		8.3%	
I <sub>TERM</sub>	Termination current regulation	$R_{ICHG} = 372 \ \Omega, \ V_{VBAT} = 4.35 \ V, \ I_{CHG} = 1.813 \ A$	56	100	126	mA
I <sub>TERM_ACC</sub>	Termination current regulation accuracy	Percentage of I <sub>CHG</sub> , R <sub>ICHG</sub> = 372 $\Omega$ , V <sub>VBAT</sub> = 4.35 V, I <sub>CHG</sub> = 1.813 A	3.0%		7.0%	
V <sub>SHORT</sub>	Battery short voltage	V <sub>VBAT</sub> falling	1.85	2	2.15	V
V <sub>SHORTZ</sub>	Battery short voltage	V <sub>VBAT</sub> rising	2.05	2.25	2.35	V
I <sub>SHORT</sub>	Battery short current	V <sub>VBAT</sub> < V <sub>SHORTZ</sub>	70	90	110	mA
V <sub>RECHG</sub>	Recharge Threshold below V <sub>BAT REG</sub>	V <sub>BAT</sub> falling	87	121	156	mV
I <sub>SYSLOAD</sub>	System discharge load current	V <sub>SYS</sub> = 4.2 V		30		mA
	E AND CURRENT REGULATION		Ų.	· ·	<del> </del>	
V <sub>DPM_VBAT</sub>	Input voltage regulation limit	V <sub>VBAT</sub> < 4.1 V (V <sub>VBAT</sub> = 3.6 V)	4.171	4.3	4.429	V
V <sub>DPM_VBAT_ACC</sub>	Input voltage regulation accuracy	V <sub>VBAT</sub> < 4.1 V (V <sub>VBAT</sub> = 3.6 V)	-3%		3%	
I <sub>INDPM</sub>	USB input current regulation limit	$V_{VBUS} = 5 \text{ V}$ , USB500 charge port detected by DPDM , $-40 \le T_J \le 85^{\circ}\text{C}$	448		500	mA
I <sub>INDPM</sub>	Input current regulation limit	$R_{ILIM} = 910~\Omega$ , unknown adaptor detected by DPDM , $-40 \le T_J \le 85^{\circ}C$	505	526	550	mA
I <sub>INDPM</sub>	Input current regulation limit accuracy	$R_{ILIM} = 374~\Omega$ , unknown adaptor detected by DPDM , $-40 \le T_J \le 85^{\circ}C$	1220	1276	1330	mA
I <sub>INDPM</sub>	Input current regulation limit	$R_{ILIM} = 265~\Omega$ , unknown adaptor detected by DPDM , $-40 \le T_J \le 85^{\circ}C$	1.73	1.8	1.871	Α
I <sub>INDPM_ACC</sub>	Input current regulation limit accuracy	$R_{ILIM} = 265~\Omega,~374~\Omega,~910~\Omega,$ unknown adaptor detected by DPDM , $-40 \le T_J \le 85^{\circ}C$	-5%		5%	
K <sub>ILIM</sub>	Input current setting ratio, I <sub>LIM</sub> = K <sub>ILIM</sub> / R <sub>ILIM</sub>	$\begin{aligned} R_{ILIM} &= 910~\Omega,~374~\Omega,~265~\Omega,\\ \text{unknown adaptor detected by}\\ \text{DPDM},~-40 &\leq T_{J} \leq 85^{\circ}\text{C} \end{aligned}$	459	478	500	Α×Ω
K <sub>ILIM_ACC</sub>	Input current setting ratio, $I_{LIM} = K_{ILIM} / R_{ILIM}$	$R_{ILIM} = 910~\Omega,~374~\Omega,~265~\Omega,$ unknown adaptor detected by DPDM, $-40 \le T_J \le 85^{\circ}C$	-5%		5%	
I <sub>IN_START</sub>	Input current limit during system start-up sequence			200		mA



 $V_{VAC\_PRESENT} < V_{VAC} < V_{VAC\_OV}$  and  $V_{VAC} > V_{BAT} + V_{SLEEP}$ ,  $T_J = -40^{\circ}C$  to 125°C and  $T_J = 25^{\circ}C$  for typical values (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
BAT PIN OVER	VOLTAGE PROTECTION					
V <sub>BATOVP_RISE</sub>	Battery overvoltage threshold	$V_{BAT}$ rising, as percentage of $V_{BAT\_REG}$	103%	104%	105%	
V <sub>BATOVP_FALL</sub>	Battery overvoltage threshold	$V_{\text{BAT}}$ falling, as percentage of $V_{\text{BAT\_REG}}$	101%	102%	103%	



 $V_{VAC\_PRESENT} < V_{VAC} < V_{VAC\_OV}$  and  $V_{VAC} > V_{BAT} + V_{SLEEP}$ ,  $T_J = -40^{\circ}C$  to 125°C and  $T_J = 25^{\circ}C$  for typical values (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
THERMAL REG	ULATION AND THERMAL SHUTDOWN					
T <sub>JUNCTION_REG</sub>	Junction Temperature Regulation Threshold			110		°C
T <sub>SHUT</sub>	Thermal Shutdown Rising Temperature	Temperature Increasing		160		°C
T <sub>SHUT_HYST</sub>	Thermal Shutdown Hysteresis			30		°C
JEITA Thermist	tor Comparator (BUCK MODE)					
V <sub>T1</sub>	T1 (0°C) threshold, Charge suspended T1 below this temperature.	Charger suspends charge. As Percentage to V <sub>REGN</sub>	72.4%	73.3%	74.2%	
V <sub>T1</sub>	Falling	As Percentage to V <sub>REGN</sub>	69%	71.5%	74%	
V <sub>T2</sub>	T2 (10°C) threshold, Charge back to I <sub>CHG</sub> /2 and 4.2 V below this temperature	As percentage of V <sub>REGN</sub>	67.2%	68%	69%	
V <sub>T2</sub>	Falling	As Percentage to V <sub>REGN</sub>	66%	66.8%	67.7%	
V <sub>T3</sub>	T3 (45°C) threshold, charge back to ICHG and 4.05V above this temperature.	Charger suspends charge. As Percentage to V <sub>REGN</sub>	43.8%	44.7%	45.8%	
V <sub>T3</sub>	Falling	As Percentage to V <sub>REGN</sub>	45.1%	45.7%	46.2%	
V <sub>T5</sub>	T5 (60°C) threshold, charge suspended above this temperature.	As Percentage to V <sub>REGN</sub>	33.7%	34.2%	35.1%	
V <sub>T5</sub>	Falling	As Percentage to V <sub>REGN</sub>	34.5%	35.3%	36.2%	
COLD OR HOT	THERMISTER COMPARATOR (BOOST N	MODE)				
V <sub>BCOLD</sub>	Cold Temperature Threshold, TS pin Voltage Rising Threshold	As Percentage to V <sub>REGN</sub> (Approx. –20°C w/ 103AT), –20°C ≤ T <sub>J</sub> ≤ 125°C	79.5%	80%	80.5%	
V <sub>BCOLD</sub>	Falling	–20°C ≤ T <sub>J</sub> ≤ 125°C	78.5%	79%	79.5%	
V <sub>внот</sub>	Hot Temperature Threshold, TS pin Voltage falling Threshold	As Percentage to $V_{REGN}$ (Approx. 60°C w/ 103AT), $-20$ °C $\leq T_J \leq 125$ °C	30.2%	31.2%	32.2%	
V <sub>BHOT</sub>	Rising	–20°C ≤ T <sub>J</sub> ≤ 125°C	33.8%	34.4%	34.9%	



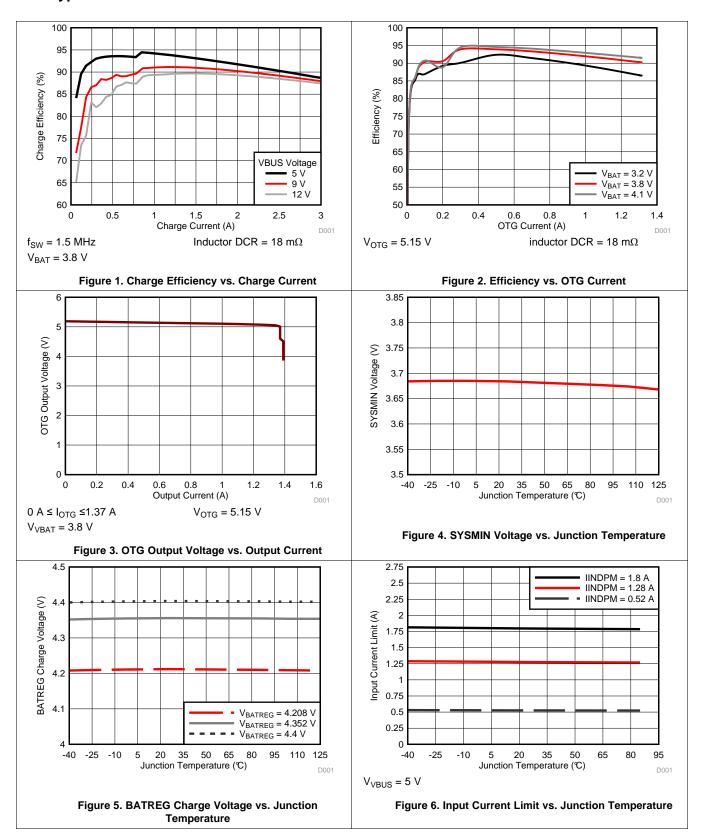
 $V_{VAC\_PRESENT} < V_{VAC} < V_{VAC\_OV}$  and  $V_{VAC} > V_{BAT} + V_{SLEEP}$ ,  $T_J = -40^{\circ}C$  to 125°C and  $T_J = 25^{\circ}C$  for typical values (unless otherwise noted)

otherwise note	•					
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
CHARGE OVER	RCURRENT COMPARATOR (CYCLE-BY-C	CYCLE)				
I <sub>HSFET_OCP</sub>	HSFET cycle-by-cycle over-current threshold		5.2		8.0	Α
I <sub>BATFET_OCP</sub>	System over load threshold		6.0			Α
PWM						
f	PWM switching frequency	Oscillator frequency, buck mode	1320	1500	1680	kHz
f <sub>SW</sub>	r www switching frequency	Oscillator frequency, boost mode	1170	1412	1500	kHz
$D_{MAX}$	Maximum PWM duty cycle <sup>(1)</sup>			97%		
BOOST MODE	OPERATION					
V <sub>OTG_REG</sub>	Boost mode regulation voltage	V <sub>VBAT</sub> = 3.8 V, I <sub>(PMID)</sub> = 0 A	4.972	5.126	5.280	V
V <sub>OTG_REG_ACC</sub>	Boost mode regulation voltage accuracy	V <sub>VBAT</sub> = 3.8 V, I <sub>(PMID)</sub> = 0 A	-3		3	%
V	Battery voltage exiting boost mode	V <sub>VBAT</sub> falling	2.6	2.8	2.9	V
$V_{BATLOWV\_OTG}$	Battery voltage entering boost mode	V <sub>VBAT</sub> rising	2.9	3.0	3.15	V
I <sub>OTG</sub>	OTG mode output current limit		1.2	1.4	1.6	Α
V <sub>OTG_OVP</sub>	OTG overvoltage threshold	Rising threshold	5.55	5.8	6.15	V
REGN LDO					·	
V <sub>REGN</sub>	REGN LDO output voltage	V <sub>VBUS</sub> = 9 V, I <sub>REGN</sub> = 40 mA	5.6	6	6.65	V
V <sub>REGN</sub>	REGN LDO output voltage	V <sub>VBUS</sub> = 5 V, I <sub>REGN</sub> = 20 mA	4.6	4.7	4.9	V
LOGIC I/O PIN	CHARACTERISTICS (CE, PSEL, SCL, SD	A,, ĪNT)				
V <sub>ILO</sub>	Input low threshold CE				0.4	V
V <sub>IH</sub>	Input high threshold CE		1.3			V
I <sub>BIAS</sub>	High-level leakage current CE	Pull up rail 1.8 V			1	μA
V <sub>ILO</sub>	Input low threshold OTG				0.4	V
$V_{IH}$	Input high threshold OTG		1.3			V
I <sub>BIAS</sub>	High-level leakage current OTG	Pull up rail 1.8 V			1	μA
LOGIC I/O PIN	CHARACTERISTICS (PG, STAT)					
V <sub>OL</sub>	Low-level output voltage				0.4	V
D+/D- DETECT	ION					
V <sub>D+_1P2</sub>	D+ Threshold for Non-standard adapter (combined V1P2_VTH_LO and V1P2_VTH_HI)		1.05		1.35	٧
I <sub>D+_LKG</sub>	Leakage current into D+	HiZ	-1		1	μA
V <sub>D600MVSRC</sub>	Voltage source (600 mV)		500	600	700	mV
I <sub>D100UAISNK</sub>	D– current sink (100 μA)	V <sub>D-</sub> = 500 mV,	50	100	150	μA
R <sub>D19K</sub>	D– resistor to ground (19 kΩ)	V <sub>D-</sub> = 500 mV,	14.25		24.8	kΩ
V <sub>D0P325</sub>	D– comparator threshold for primary detection	D- pin Rising	250		400	mV
V <sub>D2P8</sub>	D- Threshold for non-standard adapter (combined V2P8_VTH_LO and V2P8_VTH_HI)		2.55		2.85	V
V <sub>D2P0</sub>	D– Comparator threshold for non- standard adapter (For non-standard – same as bq2589x)		1.85		2.15	V
V <sub>D1P2</sub>	D– Threshold for non-standard adapter (combined V1P2_VTH_LO and V1P2_VTH_HI)		1.05		1.35	V
I <sub>DLKG</sub>	Leakage current into D-	HiZ	-1		1	μΑ

<sup>(1)</sup> Specified by design. Not production tested.



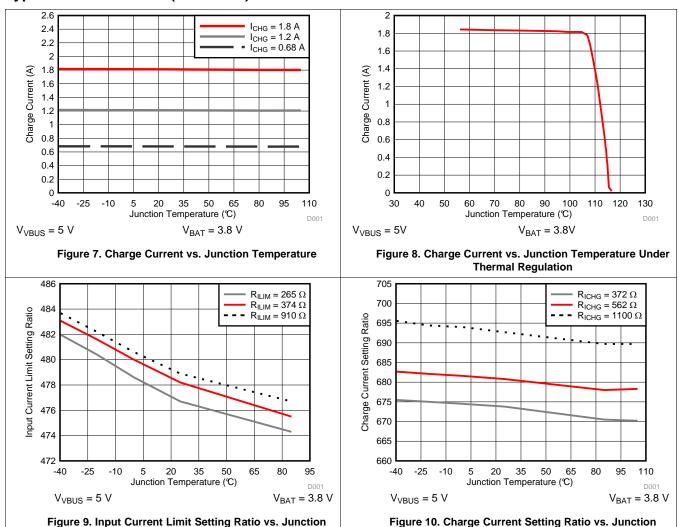
# 7.7 Typical Characteristics





# **Typical Characteristics (continued)**

**Temperature** 



**Temperature** 



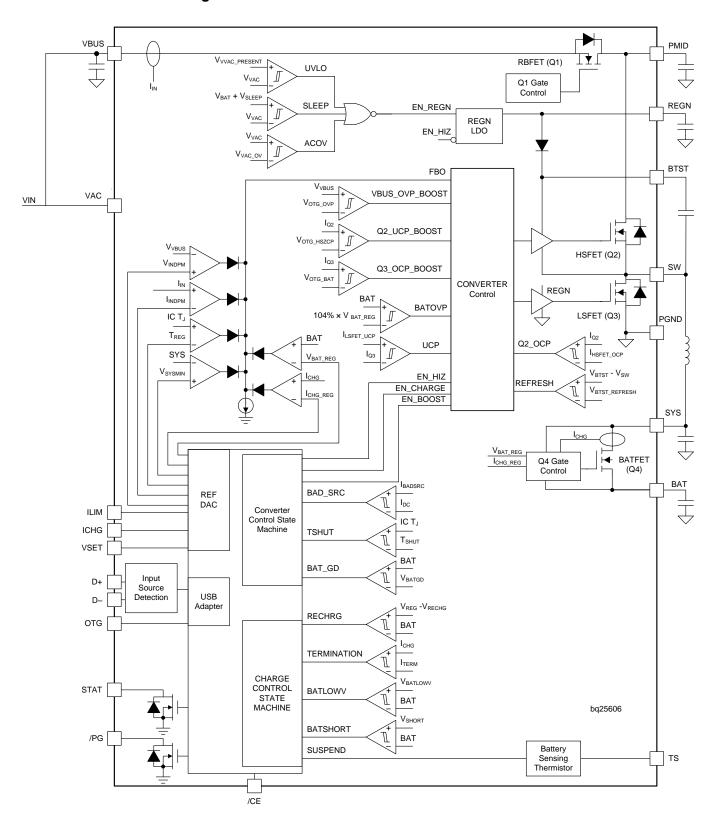
# 8 Detailed Description

# 8.1 Overview

The bq25606 device is a highly integrated 3.0-A switch-mode battery charger for single cell Li-lon and Li-polymer battery. It includes the input reverse-blocking FET (RBFET, Q1), high-side switching FET (HSFET, Q2), low-side switching FET (LSFET, Q3), and battery FET (BATFET, Q4), and bootstrap diode for the high-side gate drive.



# 8.2 Functional Block Diagram





# 8.3 Feature Description

# 8.3.1 Device Power Up from Battery without Input Source

If only battery is present and the voltage is above depletion threshold (V<sub>BAT\_DPL\_RISE)</sub>, the BATFET turns on and connects battery to system. The REGN stays off to minimize the quiescent current. The low RDSON of BATFET and the low quiescent current on BAT minimize the conduction loss and maximize the battery run time.

The device always monitors the discharge current through BATFET (Supplement Mode). When the system is overloaded or shorted ( $I_{BAT} > I_{BATFET\_OCP}$ ), the device turns off BATFET immediately until the input source plugs in again.

# 8.3.2 Power Up from Input Source

When an input source is plugged in, the device checks the input source voltage to turn on REGN LDO and all the bias circuits. It detects and sets the input current limit before the buck converter is started. The power up sequence from input source is as listed:

- 1. Power Up REGN LDO
- 2. Poor Source Qualification
- 3. Input Source Type Detection is based on D+/D- to set input current limit (IINDPM) .
- 4. Input Voltage Limit Threshold Setting (VINDPM threshold)
- 5. Converter Power-up

# 8.3.2.1 Power Up REGN Regulation

The REGN LDO supplies internal bias circuits as well as the HSFET and LSFET gate drive. The REGN also provides bias rail to TS external resistors. The pull-up rail of STAT can be connected to REGN as well. The REGN is enabled when all the below conditions are valid:

- V<sub>VAC</sub> above V<sub>VAC PRESENT</sub>
- V<sub>VAC</sub> above V<sub>BAT</sub> + V<sub>SLEEPZ</sub> in buck mode or VBUS below V<sub>BAT</sub> + V<sub>SLEEP</sub> in boost mode
- · After 220-ms delay is completed

If any one of the above conditions is not valid, the device is in high impedance mode (HIZ) with REGN LDO off. The device draws less than IVBUS\_HIZ from VBUS during HIZ state. The battery powers up the system when the device is in HIZ.

#### 8.3.2.2 Poor Source Qualification

After REGN LDO powers up, the device confirms the current capability of the input source. The input source must meet both of the following requirements in order to start the buck converter.

- VAC voltage below V<sub>VAC OV</sub>
- VBUS voltage above V<sub>VBUSMIN</sub> when pulling I<sub>BADSRC</sub> (typical 30 mA)

If the device fails the poor source detection, it repeats poor source qualification every 2 seconds.

# 8.3.2.3 Input Source Type Detection

After the REGN LDO is powered, the device runs input source detection through D+/D- lines. The bq25606 follows the USB Battery Charging Specification 1.2 (BC1.2) to detect input source (SDP/ DCP) and non-standard adapter through USB D+/D- lines. The bq25606 sets input current limit through D+/D- detection and ILIM pins.

#### 8.3.2.3.1 D+/D- Detection Sets Input Current Limit in bq25606

The bq25606 contains a D+/D- based input source detection to set the input current limit at VBUS plug-in. The D+/D- detection includes standard USB BC1.2 and non-standard adapter. When input source is plugged in, the device starts standard USB BC1.2 detections. The USB BC1.2 is capable to identify Standard Downstream Port (SDP) and Dedicated Charging Port (DCP). When the Data Contact Detection (DCD) timer expires, the non-standard adapter detection is applied to set the input current limit. The non-standard detection is used to distinguish vendor specific adapters (Apple and Samsung) based on their unique dividers on the D+/D- pins. If an adapter is detected as DCP, the input current limit is set at 2.4 A. If an adapter is detected as unknown, the input current limit is set by ILIM pin.



# Feature Description (接下页)

# 表 1. Non-Standard Adapter Detection

Non-Standard Adapter	D+ Threshold	D- Threshold	Input Current Limit (A)
Divider 1	V <sub>D+</sub> within V <sub>2P7_VTH</sub>	V <sub>D</sub> _ within V <sub>2P0_VTH</sub>	2.1
Divider 2	V <sub>D+</sub> within V <sub>1P2_VTH</sub>	V <sub>D</sub> within V <sub>1P2_VTH</sub>	2
Divider 3	V <sub>D+</sub> within V <sub>2P0_VTH</sub>	V <sub>D</sub> within V <sub>2P7_VTH</sub>	1
Divider 4	V <sub>D+</sub> within V <sub>2P7_VTH</sub>	V <sub>D</sub> within V <sub>2P7_VTH</sub>	2.4

# 表 2. Input Current Limit Setting from D+/D- Detection

D+/D- Detection	Input Current Limit (IINLIM)
USB SDP (USB500)	500 mA
USB DCP	2.4 A
Divider 3	1 A
Divider 1	2.1 A
Divider 4	2.4 A
Divider 2	2 A
Unknown 5-V Adapter	Set by ILIM pin

# 8.3.2.4 Input Voltage Limit Threshold Setting (VINDPM Threshold)

The device's VINDPM is set at 4.3V. The device supports dynamic VINDPM tracking which tracks the battery voltage. The device's VINDPM tracks battery voltage with 200mV offset such that when VBAT + 200mV is greater than 4.3V, the VINDPM value is automatically adjusted to VBAT + 200mV.

#### 8.3.2.5 Converter Power-Up

After the input current limit is set, the converter is enabled and the HSFET and LSFET start switching. If battery charging is disabled, BATFET turns off. Otherwise, BATFET stays on to charge the battery.

The device provides soft-start when system rail is ramped up. When the system rail is below 2.2 V, the input current is limited to is to 200 mA. After the system rises above 2.2 V, the device limits input current to the value set by ILIM pin.

As a battery charger, the device deploys a highly efficient 1.5 MHz step-down switching regulator. The fixed frequency oscillator keeps tight control of the switching frequency under all conditions of input voltage, battery voltage, charge current and temperature, simplifying output filter design.

The device switches to PFM control at light load or when battery is below minimum system voltage setting or charging is disabled.

# 8.3.3 Boost Mode Operation From Battery

The device supports boost converter operation to deliver power from the battery to other portable devices through USB port. The maximum output current is up to 1.2 A. The boost operation can be enabled if the conditions are valid:

- 1. BAT above V<sub>OTG BAT</sub>
- 2. VBUS less than BAT+V<sub>SLEEP</sub> (in sleep mode)
- 3. Boost mode operation is enabled (OTG pin HIGH)
- 4. Voltage at TS (thermistor) pin is within acceptable range ( $V_{BHOT} < V_{TS} < V_{BCOLD}$ )
- 5. After 30-ms delay from boost mode enable

During boost mode, the VBUS output is 5.15 V and the output current can reach up to 1.2 A. The boost output is maintained when BAT is above  $V_{OTG\_BAT}$  threshold.

When OTG is enabled, the device starts up with PFM and later transits to PWM to minimize the overshoot.



# 8.3.4 Standalone Power Management

# 8.3.5 Power Path Management

The device accommodates a wide range of input sources from USB, wall adapter, to car charger. The device provides automatic power path selection to supply the system (SYS) from input source (VBUS), battery (BAT), or both.

# 8.3.6 Battery Charging Management

The device charges 1-cell Li-lon battery with up to 3.0-A charge current for high capacity tablet battery. The 19.5- $m\Omega$  BATFET improves charging efficiency and minimize the voltage drop during discharging.

# 8.3.6.1 Autonomous Charging Cycle

With battery charging is enabled ( $\overline{CE}$  pin is LOW), the device autonomously completes a charging cycle. The device default charging parameters are listed in  $\frac{1}{5}$  3.

	_
Default Mode	bq25606
Charging voltage	VSET controlled
Charging current	I <sub>CHG</sub> controlled
Pre-charge current	5% of ICHG
Termination current	5% of ICHG
Temperature profile	JEITA
Safety timer	10 hours

表 3. Charging Parameter Default Setting

A new charge cycle starts when the following conditions are valid:

- · Converter starts
- Battery charging is enabled (CE is low)
- · No thermistor fault on TS
- · No safety timer fault

The charger device automatically terminates the charging cycle when the charging current is below termination threshold, battery voltage is above recharge threshold, and device not is in DPM mode or thermal regulation. When a fully charged battery is discharged below recharge threshold, the device automatically starts a new charging cycle. After the charge is done, toggle  $\overline{CE}$  pin can initiate a new charging cycle.

The STAT output indicates the charging status: charging (LOW), charging complete or charge disable (HIGH) or charging fault (Blinking).

# 8.3.6.2 Charging Termination

The device terminates a charge cycle when the battery voltage is above recharge threshold, and the current is below termination current. After the charging cycle is completed, the BATFET turns off. The converter keeps running to power the system, and BATFET can turn on again to engage *Supplement Mode*.

# 8.3.6.3 Thermistor Qualification

The charger device provides a single thermistor input for battery temperature monitor.

#### 8.3.6.4 JEITA Guideline Compliance During Charging Mode

To improve the safety of charging Li-ion batteries, JEITA guideline was released on April 20, 2007. The guideline emphasized the importance of avoiding a high charge current and high charge voltage at certain low and high temperature ranges.

To initiate a charge cycle, the voltage on TS pin must be within the VT1 to VT5 thresholds. If TS voltage exceeds the T1-T5 range, the controller suspends charging and waits until the battery temperature is within the T1 to T5 range.



At cool temperature (T1-T2), the charge current is reduced to 20% of programmed fast charge current. At warm temperature (T3-T5), the charge voltage is reduced to 4.1 V.

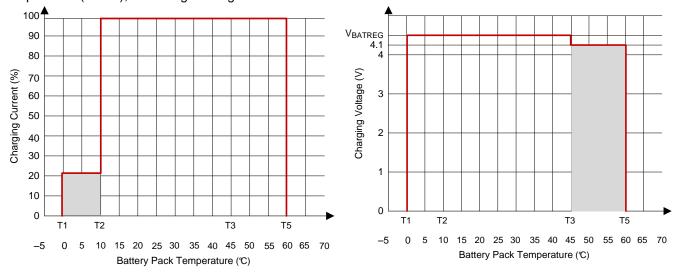


图 11. JEITA Profile: Charging Current

图 12. JEITA Profile: Charging Voltage

公式 1 through 公式 2 describe updates to the resistor bias network.

$$RT2 = \frac{V_{REGN} \times RTH_{COLD} \times RTH_{HOT} \times \left(\frac{1}{VT1} - \frac{1}{VT5}\right)}{RTH_{HOT} \times \left(\frac{V_{REGN}}{VT5} - 1\right) - RTH_{COLD} \times \left(\frac{V_{REGN}}{VT1} - 1\right)}$$

$$RT1 = \frac{\left(\left(\frac{V_{REGN}}{VT1}\right) - 1\right)}{\left(\frac{1}{RT2}\right) + \left(\frac{1}{RTH_{COLD}}\right)}$$
(2)

Select 0°C to 60°C range for Li-ion or Li-polymer battery:

- RTH<sub>COLD</sub> = 27.28 K $\Omega$
- RTH<sub>HOT</sub> = 3.02 KΩ
- RT1 = 5.23 K $\Omega$
- RT2 = 30.9 KΩ

# 8.3.6.5 Boost Mode Thermistor Monitor during Battery Discharge Mode

For battery protection during boost mode, the device monitors the battery temperature to be within the to thresholds. When temperature is outside of the temperature thresholds, the boost mode is suspended.



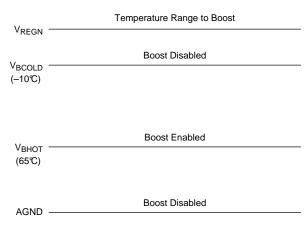


图 13. TS Pin Thermistor Sense Threshold in Boost Mode

# 8.3.6.6 Charging Safety Timer

The device has built-in safety timer to prevent extended charging cycle due to abnormal battery conditions. The safety timer is 2 hours when the battery is below  $V_{BATLOWV}$  threshold and 10 hours when the battery is higher than  $V_{BATLOWV}$  threshold.

During input voltage, current, JEITA cool or thermal regulation, the safety timer counts at half clock rate as the actual charge current is likely to be below the register setting. For example, if the charger is in input current regulation throughout the whole charging cycle, the safety timer will expire in 20 hours.

During the fault, timer is suspended. Once the fault goes away, fault resumes. If user stops the current charging cycle, and start again, timer gets reset.

#### 8.3.6.7 Narrow VDC Architecture

The device deploys Narrow VDC architecture (NVDC) with BATFET separating system from battery. The minimum system voltage is set by SYS\_Min bits. Even with a fully depleted battery, the system is regulated above the minimum system voltage.

When the battery is below minimum system voltage setting, the BATFET operates in linear mode (LDO mode), and the system is typically 180 mV above the minimum system voltage setting. As the battery voltage rises above the minimum system voltage, BATFET is fully on and the voltage difference between the system and battery is the VDS of BATFET.

When the battery charging is disabled and above minimum system voltage setting or charging is terminated, the system is always regulated at typically 50mV above battery voltage..

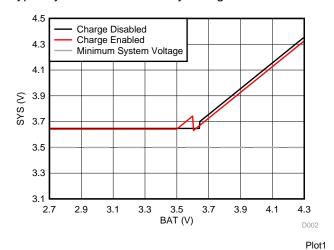


图 14. System Voltage vs Battery Voltage



# 8.3.6.8 Dynamic Power management

To meet maximum current limit in USB spec and avoid over loading the adapter, the device features Dynamic Power management (DPM), which continuously monitors the input current and input voltage. When input source is over-loaded, either the current exceeds the input current limit (IIDPM) or the voltage falls below the input voltage limit (VINDPM). The device then reduces the charge current until the input current falls below the input current limit and the input voltage rises above the input voltage limit.

When the charge current is reduced to zero, but the input source is still overloaded, the system voltage starts to drop. Once the system voltage falls below the battery voltage, the device automatically enters the supplement mode where the BATFET turns on and battery starts discharging so that the system is supported from both the input source and battery.

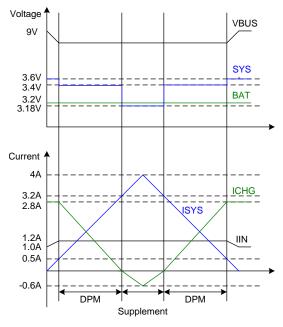


图 15. DPM Response

# 8.3.6.9 Supplement Mode

When the system voltage falls 180 mV (VBAT > VSYSMin) or 45 mV (VBAT < VSYSMin) below the battery voltage, the BATFET turns on and the BATFET gate is regulated the gate drive of BATFET so that the minimum BATFET VDS stays at 30 mV when the current is low. This prevents oscillation from entering and exiting the supplement mode.

As the discharge current increases, the BATFET gate is regulated with a higher voltage to reduce RDSON until the BATFET is in full conduction. At this point onwards, the BATFET VDS linearly increases with discharge current. 

16 shows the V-I curve of the BATFET gate regulation operation. BATFET turns off to exit supplement mode when the battery is below battery depletion threshold.

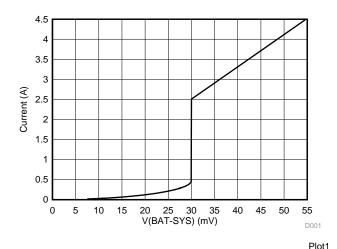


图 16. BAFET V-I Curve

# 8.3.7 Status Outputs (PG, STAT)

# 8.3.7.1 Power Good indicator (PG Pin)

The PG pin goes LOW to indicate a good input source when:

- VBUS above V<sub>VBUS\_UVLO</sub>
- VBUS above battery (not in sleep)
- VBUS below V<sub>VAC OV</sub> threshold
- VBUS above V<sub>VBUSMin</sub> (typical 3.8 V) when I<sub>BADSRC</sub> (typical 30 mA) current is applied (not a poor source)
- Completed input Source Type Detection

#### 8.3.7.2 Charging Status indicator (STAT)

The device indicates charging state on the open drain STAT pin. The STAT pin can drive LED.

# 表 4. STAT Pin State

CHARGING STATE	STAT INDICATOR
Charging in progress (including recharge)	LOW
Charging complete	HIGH
Sleep mode, charge disable	HIGH
Charge suspend (input overvoltage, TS fault, timer fault or system overvoltage) Boost Mode suspend (due to TS fault)	Blinking at 1 Hz

#### 8.3.8 Protections

# 8.3.8.1 Input Current Limit

The device's ILIM pin is to program maximum input current when D+/D- detection identifies an unknown adaptor plugged in. The maximum input current is set by a resistor from ILIM pin to ground as:

$$I_{\text{INMAX}} = \frac{K_{\text{ILIM}}}{R_{\text{ILIM}}} \tag{3}$$

#### 8.3.8.2 Voltage and Current Monitoring in Converter Operation

The device closely monitors the input and system voltage, as well as internal FET currents for safe buck and boost mode operation.



#### 8.3.8.2.1 Voltage and Current Monitoring in Buck Mode

#### 8.3.8.2.1.1 Input Overvoltage (ACOV)

If VAC exceeds V<sub>VAC OV</sub>, HSFET stops switching immediately.

# 8.3.8.2.1.2 System Overvoltage Protection (SYSOVP)

The charger device clamps the system voltage during load transient so that the components connect to system would not be damaged due to high voltage. SYSOVP threshold is 350 mV above minimum system regulation voltage when the system is regulate at  $V_{SYSMIN}$ . Upon SYSOVP, converter stops switching immediately to clamp the overshoot. The charger provides 30 mA discharge current to bring down the system voltage.

# 8.3.8.3 Voltage and Current Monitoring in Boost Mode

The device closely monitors the VBUS voltage, as well as RBFET and LSFET current to ensure safe boost mode operation.

#### 8.3.8.3.1 VBUS Soft Start

When the boost function is enabled, the device soft-starts boost mode to avoid inrush current.

#### 8.3.8.3.2 VBUS Output Protection

The device monitors boost output voltage and other conditions to provide output short circuit and overvoltage protection. The Boost build in accurate constant current regulation to allow OTG to adaptive to various types of load. If short circuit is detected on VBUS, the Boost turns off and retry 7 times. If retries are not successful, OTG is disabled.

#### 8.3.8.3.3 Boost Mode Overvoltage Protection

When the VBUS voltage rises above regulation target and exceeds VOTG OVP, the device stop switching.

# 8.3.8.4 Thermal Regulation and Thermal Shutdown

#### 8.3.8.4.1 Thermal Protection in Buck Mode

The bq25606 monitors the internal junction temperature  $T_J$  to avoid overheat the chip and limits the IC surface temperature in buck mode. When the internal junction temperature exceeds thermal regulation limit (110°C), the device lowers down the charge current. During thermal regulation, the actual charging current is usually below the programmed battery charging current. Therefore, termination is disabled, the safety timer runs at half the clock rate.

#### 8.3.8.4.2 Thermal Protection in Boost Mode

The device monitors the internal junction temperature to provide thermal shutdown during boost mode. When IC junction temperature exceeds  $T_{SHUT}$  (160°C), the boost mode is disabled and BATFET is turned off. When IC junction temperature is below  $T_{SHUT}(160^{\circ}\text{C})$  -  $T_{SHUT\_HYS}$  (30°C), the BATFET is enabled automatically to allow system to restore .

#### 8.3.8.5 Battery Protection

#### 8.3.8.5.1 Battery overvoltage Protection (BATOVP)

The battery overvoltage limit is clamped at 4% above the battery regulation voltage. When battery over voltage occurs, the charger device immediately disables charging.

# 8.3.8.5.2 Battery Over-Discharge Protection

When battery is discharged below  $V_{BAT\_DPL\_FALL}$ , the BATFET is turned off to protect battery from over discharge. To recover from over-discharge latch-off, an input source plug-in is required at VBUS. The battery is charged with  $I_{SHORT}$  (typically 100 mA) current when the VBAT < VSHORT, or precharge current as set by 5% of ICHG when the battery voltage is between  $V_{SHORTZ}$  and  $V_{BAT\_LOWV}$ .



#### 8.3.8.5.3 System Over-Current Protection

When the system is shorted or significantly overloaded (IBAT > IBATOP) and the current exceeds BATFET overcurrent limit, the BATFET latches off. The BATFET latch can be reset with VBUS plug-in.

# 9 Application and Implementation

注

information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

# 9.1 Application information

A typical application consists of the device configured as a stand-alone power path management device and a single cell battery charger for Li-Ion and Li-polymer batteries used in a wide range of smart phones and other portable devices. It integrates an input reverse-block FET (RBFET, Q1), high-side switching FET (HSFET, Q2), low-side switching FET (LSFET, Q3), and battery FET (BATFET Q4) between the system and battery. The device also integrates a bootstrap diode for the high-side gate drive.



# 9.2 Typical Application Diagram

# 图 17. Power Path Management Application

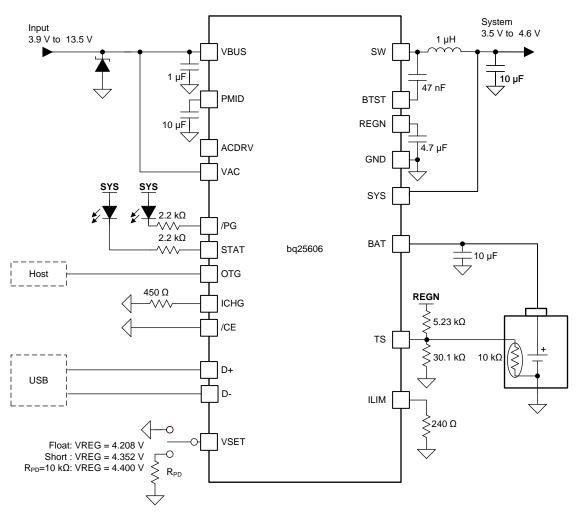


图 18. bq25606 Application Diagram

#### 9.2.1 Design Requirements

#### 9.2.2 Detailed Design Procedure

#### 9.2.2.1 inductor Selection

The 1.5-MHz switching frequency allows the use of small inductor and capacitor values to maintain an inductor saturation current higher than the charging current ( $I_{CHG}$ ) plus half the ripple current ( $I_{RIPPLE}$ ):

$$I_{SAT} \ge I_{CHG} + (1/2) I_{RIPPLE} \tag{4}$$

The inductor ripple current depends on the input voltage ( $V_{VBUS}$ ), the duty cycle ( $D = V_{BAT}/V_{VBUS}$ ), the switching frequency ( $f_S$ ) and the inductance (L).

$$I_{RIPPLE} = \frac{V_{IN} \times D \times (1 - D)}{fs \times L}$$
(5)

The maximum inductor ripple current occurs when the duty cycle (D) is 0.5 or approximately 0.5. Usually inductor ripple is designed in the range between 20% and 40% maximum charging current as a trade-off between inductor size and efficiency for a practical design.



# Typical Application Diagram (接下页)

# 9.2.2.2 input Capacitor

Design input capacitance to provide enough ripple current rating to absorb input switching ripple current. The worst case RMS ripple current is half of the charging current when duty cycle is 0.5. If the converter does not operate at 50% duty cycle, then the worst case capacitor RMS current  $I_{Cin}$  occurs where the duty cycle is closest to 50% and can be estimated using  $\Delta \vec{x}$  6.

$$I_{CIN} = I_{CHG} \times \sqrt{D \times (1 - D)}$$
(6)

Low ESR ceramic capacitor such as X7R or X5R is preferred for input decoupling capacitor and should be placed to the drain of the high-side MOSFET and source of the low-side MOSFET as close as possible. Voltage rating of the capacitor must be higher than normal input voltage level. A rating of 25-V or higher capacitor is preferred for 15 V input voltage. Capacitance of 22-µF is suggested for typical of 3A charging current.

# 9.2.2.3 Output Capacitor

Ensure that the output capacitance has enough ripple current rating to absorb the output switching ripple current. 公式 7 shows the output capacitor RMS current I<sub>COUT</sub> calculation.

$$I_{COUT} = \frac{I_{RIPPLE}}{2 \times \sqrt{3}} \approx 0.29 \times I_{RIPPLE}$$
(7)

The output capacitor voltage ripple can be calculated as follows:

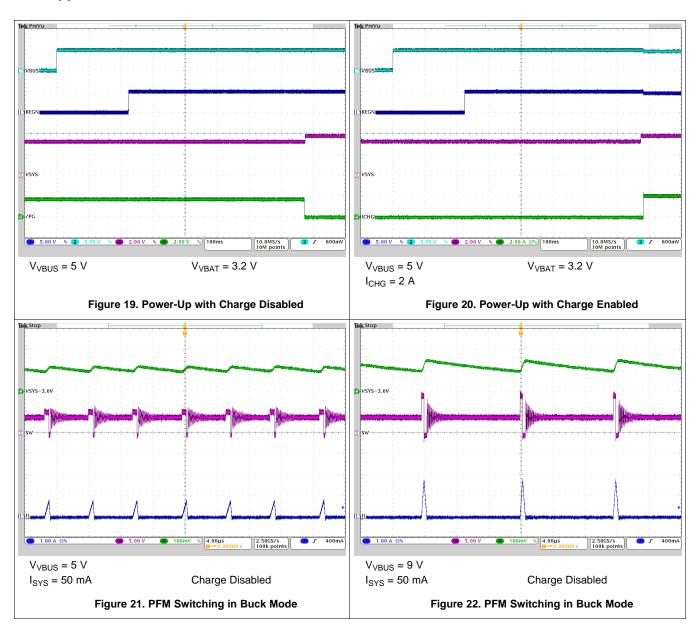
$$\Delta V_{O} = \frac{V_{OUT}}{8LCfs^{2}} \left( 1 - \frac{V_{OUT}}{V_{IN}} \right)$$
(8)

At certain input and output voltage and switching frequency, the voltage ripple can be reduced by increasing the output filter LC.

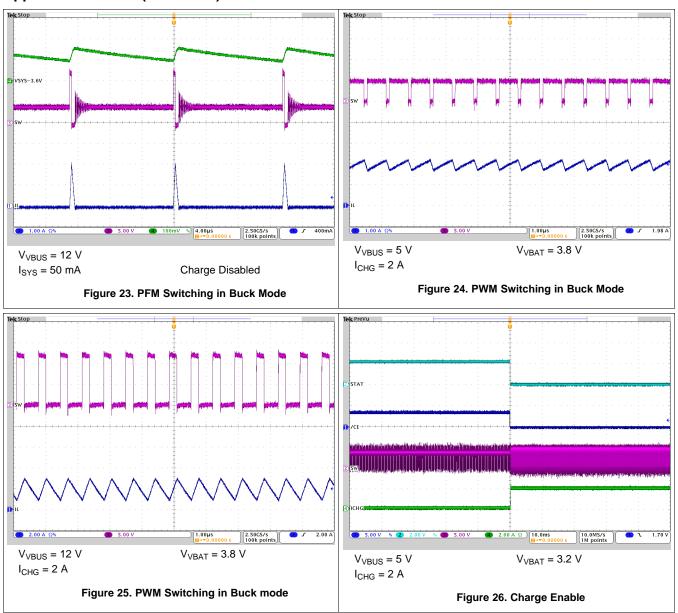
The charger device has internal loop compensation optimized for >20μF ceramic output capacitance. The preferred ceramic capacitor is 10V rating, X7R or X5R.



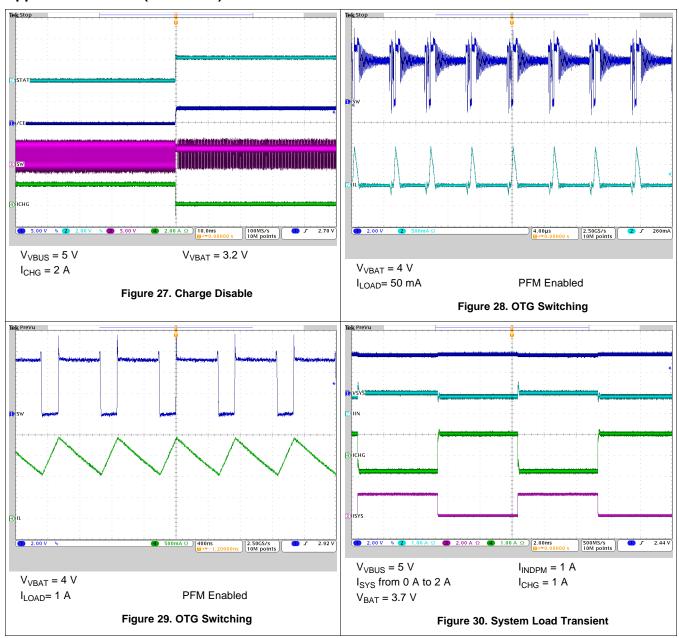
# 9.3 Application Curves



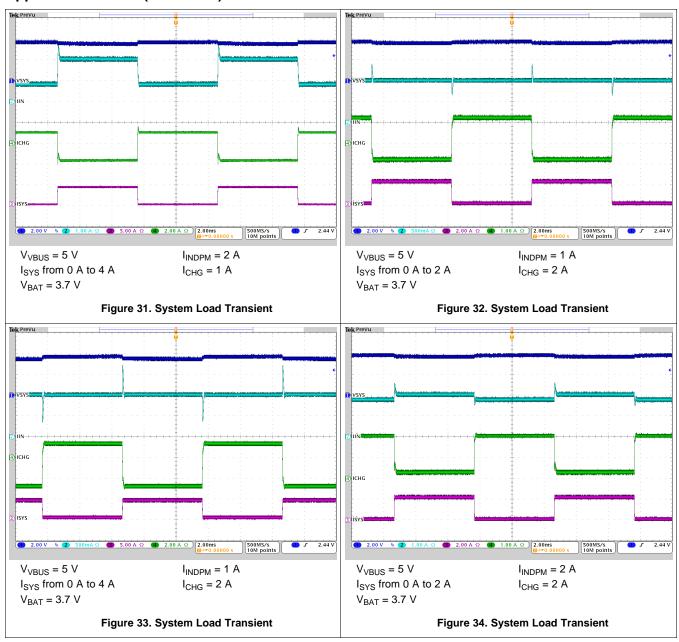




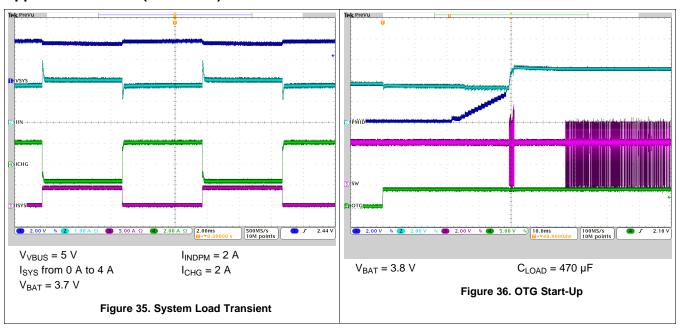














# 10 Power Supply Recommendations

in order to provide an output voltage on SYS, the bq25606 device requires a power supply between 3.9 V and 14.2 V input with at least 100-mA current rating connected to VBUS and a single-cell Li-lon battery with voltage >  $V_{BATUVLO}$  connected to BAT. The source current rating needs to be at least 3 A in order for the buck converter of the charger to provide maximum output power to SYS.



# 11 Layout

# 11.1 Layout Guidelines

The switching node rise and fall times should be minimized for minimum switching loss. Proper layout of the components to minimize high frequency current path loop (see § 37) is important to prevent electrical and magnetic field radiation and high frequency resonant problems. Follow this specific order carefully to achieve the proper layout.

- 1. Place input capacitor as close as possible to PMID pin and GND pin connections and use shortest copper trace connection or GND plane.
- Place inductor input pin to SW pin as close as possible. Minimize the copper area of this trace to lower electrical and magnetic field radiation but make the trace wide enough to carry the charging current. Do not use multiple layers in parallel for this connection. Minimize parasitic capacitance from this area to any other trace or plane.
- 3. Put output capacitor near to the inductor and the device. Ground connections need to be tied to the IC ground with a short copper trace connection or GND plane.
- 4. Route analog ground separately from power ground. Connect analog ground and connect power ground separately. Connect analog ground and power ground together using thermal pad as the single ground connection point. Or using a  $0-\Omega$  resistor to tie analog ground to power ground.
- 5. Use single ground connection to tie charger power ground to charger analog ground. Just beneath the device. Use ground copper pour but avoid power pins to reduce inductive and capacitive noise coupling.
- 6. Place decoupling capacitors next to the IC pins and make trace connection as short as possible.
- 7. It is critical that the exposed thermal pad on the backside of the device package be soldered to the PCB ground. Ensure that there are sufficient thermal vias directly under the IC, connecting to the ground plane on the other layers.
- 8. Ensure that the number and sizes of vias allow enough copper for a given current path.

See the EVM user's guide SLUUBL3 for the recommended component placement with trace and via locations. For the VQFN information, refer to SCBA017 and SLUA271.

# 11.2 Layout Example

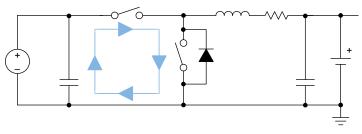


图 37. High Frequency Current Path



# Layout Example (接下页)

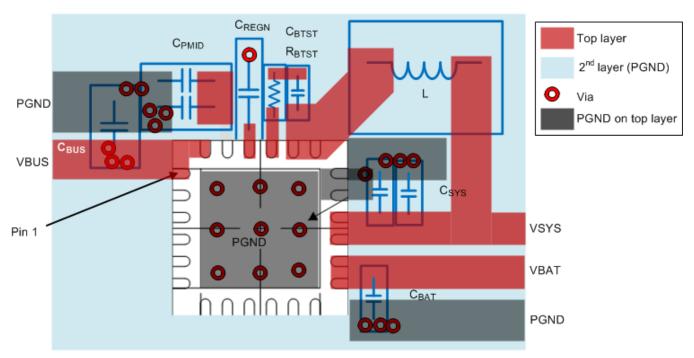


图 38. Layout Example



www.ti.com.cn

# 12 器件和文档支持

# 12.1 文档支持

#### 12.1.1 相关链接

下面的表格列出了快速访问链接。类别包括技术文档、支持与社区资源、工具和软件,以及申请样片或购买产品的快速链接。

# 12.2 社区资源

下列链接提供到 TI 社区资源的连接。链接的内容由各个分销商"按照原样"提供。这些内容并不构成 TI 技术规范,并且不一定反映 TI 的观点;请参阅 TI 的 《使用条款》。

TI E2E™ 在线社区 TI 的工程师对工程师 (E2E) 社区。此社区的创建目的在于促进工程师之间的协作。在 e2e.ti.com 中,您可以咨询问题、分享知识、拓展思路并与同行工程师一道帮助解决问题。

设计支持 71 参考设计支持 可帮助您快速查找有帮助的 E2E 论坛、设计支持工具以及技术支持的联系信息。

# 12.3 商标

E2E is a trademark of Texas Instruments.

WEBENCH is a registered trademark of Texas Instruments.

#### 12.4 静电放电警告



这些装置包含有限的内置 ESD 保护。 存储或装卸时,应将导线一起截短或将装置放置于导电泡棉中,以防止 MOS 门极遭受静电损伤。

# 12.5 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.



# 13 机械、封装和可订购信息

以下页面包含机械、封装和可订购信息。这些信息是指定器件的最新可用数据。这些数据如有变更,恕不另行通知和修订此文档。如欲获取此产品说明书的浏览器版本,请参阅左侧的导航。



# PACKAGE OPTION ADDENDUM

22-Sep-2017

#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
BQ25606RGER	ACTIVE	VQFN	RGE	24	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ25606	Samples
BQ25606RGET	ACTIVE	VQFN	RGE	24	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ25606	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

**Important Information and Disclaimer:** The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.





22-Sep-2017

PLASTIC QUAD FLATPACK - NO LEAD



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4204104/H



PLASTIC QUAD FLATPACK- NO LEAD



NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK- NO LEAD



NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- Solder mask tolerances between and around signal pads can vary based on board fabrication site.



PLASTIC QUAD FLATPACK- NO LEAD



NOTES: (continued)

Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations..



#### 重要声明

德州仪器 (TI) 公司有权按照最新发布的 JESD46 对其半导体产品和服务进行纠正、增强、改进和其他修改,并不再按最新发布的 JESD48 提供任何产品和服务。买方在下订单前应获取最新的相关信息,并验证这些信息是否完整且是最新的。

TI 公布的半导体产品销售条款 (http://www.ti.com/sc/docs/stdterms.htm) 适用于 TI 已认证和批准上市的已封装集成电路产品的销售。另有其他条款可能适用于其他类型 TI 产品及服务的使用或销售。

复制 TI 数据表上 TI 信息的重要部分时,不得变更该等信息,且必须随附所有相关保证、条件、限制和通知,否则不得复制。TI 对该等复制文件不承担任何责任。第三方信息可能受到其它限制条件的制约。在转售 TI 产品或服务时,如果存在对产品或服务参数的虚假陈述,则会失去相关 TI 产品或服务的明示或暗示保证,且构成不公平的、欺诈性商业行为。TI 对此类虚假陈述不承担任何责任。

买方和在系统中整合 TI 产品的其他开发人员(总称"设计人员")理解并同意,设计人员在设计应用时应自行实施独立的分析、评价和判断,且应全权负责并确保应用的安全性,及设计人员的应用(包括应用中使用的所有 TI 产品)应符合所有适用的法律法规及其他相关要求。设计人员就自己设计的应用声明,其具备制订和实施下列保障措施所需的一切必要专业知识,能够 (1) 预见故障的危险后果,(2) 监视故障及其后果,以及 (3) 降低可能导致危险的故障几率并采取适当措施。设计人员同意,在使用或分发包含 TI 产品的任何应用前,将彻底测试该等应用和和该等应用所用 TI 产品的功能而设计。

TI 提供技术、应用或其他设计建议、质量特点、可靠性数据或其他服务或信息,包括但不限于与评估模块有关的参考设计和材料(总称"TI 资源"),旨在帮助设计人员开发整合了 TI 产品的 应用, 如果设计人员(个人,或如果是代表公司,则为设计人员的公司)以任何方式下载、访问或使用任何特定的 TI 资源,即表示其同意仅为该等目标,按照本通知的条款使用任何特定 TI 资源。

TI 所提供的 TI 资源,并未扩大或以其他方式修改 TI 对 TI 产品的公开适用的质保及质保免责声明;也未导致 TI 承担任何额外的义务或责任。TI 有权对其 TI 资源进行纠正、增强、改进和其他修改。除特定 TI 资源的公开文档中明确列出的测试外,TI 未进行任何其他测试。

设计人员只有在开发包含该等 TI 资源所列 TI 产品的 应用时,才被授权使用、复制和修改任何相关单项 TI 资源。但并未依据禁止反言原则或其他法理授予您任何TI知识产权的任何其他明示或默示的许可,也未授予您 TI 或第三方的任何技术或知识产权的许可,该等产权包括但不限于任何专利权、版权、屏蔽作品权或与使用TI产品或服务的任何整合、机器制作、流程相关的其他知识产权。涉及或参考了第三方产品或服务的信息不构成使用此类产品或服务的许可或与其相关的保证或认可。使用 TI 资源可能需要您向第三方获得对该等第三方专利或其他知识产权的许可。

TI 资源系"按原样"提供。TI 兹免除对资源及其使用作出所有其他明确或默认的保证或陈述,包括但不限于对准确性或完整性、产权保证、无屡发故障保证,以及适销性、适合特定用途和不侵犯任何第三方知识产权的任何默认保证。TI 不负责任何申索,包括但不限于因组合产品所致或与之有关的申索,也不为或对设计人员进行辩护或赔偿,即使该等产品组合已列于 TI 资源或其他地方。对因 TI 资源或其使用引起或与之有关的任何实际的、直接的、特殊的、附带的、间接的、惩罚性的、偶发的、从属或惩戒性损害赔偿,不管 TI 是否获悉可能会产生上述损害赔偿,TI 概不负责。

除 TI 己明确指出特定产品已达到特定行业标准(例如 ISO/TS 16949 和 ISO 26262)的要求外,TI 不对未达到任何该等行业标准要求而承担任何责任。

如果 TI 明确宣称产品有助于功能安全或符合行业功能安全标准,则该等产品旨在帮助客户设计和创作自己的 符合 相关功能安全标准和要求的应用。在应用内使用产品的行为本身不会 配有 任何安全特性。设计人员必须确保遵守适用于其应用的相关安全要求和 标准而设计。设计人员不可将任何 TI 产品用于关乎性命的医疗设备,除非已由各方获得授权的管理人员签署专门的合同对此类应用专门作出规定。关乎性命的医疗设备是指出现故障会导致严重身体伤害或死亡的医疗设备(例如生命保障设备、心脏起搏器、心脏除颤器、人工心脏泵、神经刺激器以及植入设备)。此类设备包括但不限于,美国食品药品监督管理局认定为 III 类设备的设备,以及在美国以外的其他国家或地区认定为同等类别设备的所有医疗设备。

TI 可能明确指定某些产品具备某些特定资格(例如 Q100、军用级或增强型产品)。设计人员同意,其具备一切必要专业知识,可以为自己的应用选择适合的 产品, 并且正确选择产品的风险由设计人员承担。设计人员单方面负责遵守与该等选择有关的所有法律或监管要求。

设计人员同意向 TI 及其代表全额赔偿因其不遵守本通知条款和条件而引起的任何损害、费用、损失和/或责任。

邮寄地址: 上海市浦东新区世纪大道 1568 号中建大厦 32 楼,邮政编码: 200122 Copyright © 2018 德州仪器半导体技术(上海)有限公司